

## Problem 1

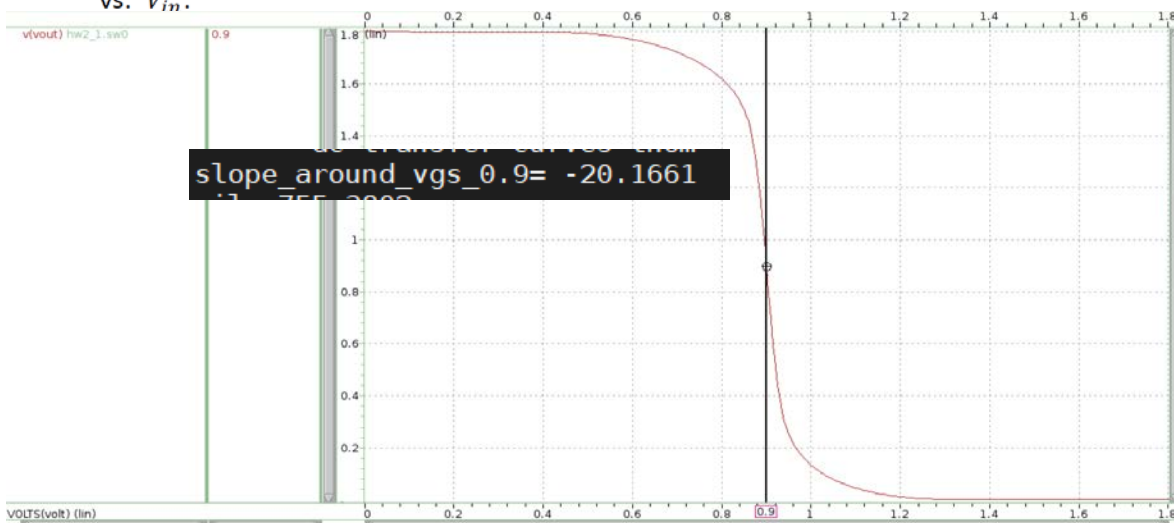
- a. Find and report the PMOS size such that the transition point happens at  $V_{out} = 0.5 \cdot V_{DD}$  when  $V_{in}$  is also  $0.5 \cdot V_{DD}$ .

ANS:  $W/L = 6.07\mu/0.2\mu$

- b. What is the ratio between PMOS and NMOS? Why?

ANS:  $\frac{(W/L)_p}{(W/L)_n} = 3.37$ , and assume  $\beta = 1$  (transition point is  $0.5V_{DD}$ ). So, the ratio  $\frac{(W/L)_p}{(W/L)_n} = \frac{\mu_n}{\mu_p}$ , consistent with the fact  $\mu_n$  is 2~3 times larger than  $\mu_p$

- c. Simulate and plot the DC voltage transfer curve of this inverter as  $V_{out}$  vs.  $V_{in}$ .



- d. Find the values of  $V_{IL}$ ,  $V_{OH}$ ,  $V_{IH}$ , and  $V_{OL}$  at points with slope of  $-1$ .

hspice code

```
.meas DC VIL when deriv('V(Vout)') = -1 fall = 1 $deriv('V(Vout) v.s Vin graph
.meas DC VOH find V(VOUT) when deriv('V(VOUT)') = -1 fall = 1
.meas DC VIH when deriv('V(Vout)') = -1 rise = 1 $deriv('V(Vout) v.s Vin graph
.meas DC VOL find V(VOUT) when deriv('V(VOUT)') = -1 rise = 1
```

ANS:

```
vil= 755.2349m
voh= 1.6757
vih= 1.0349
vol= 92.3174m
```

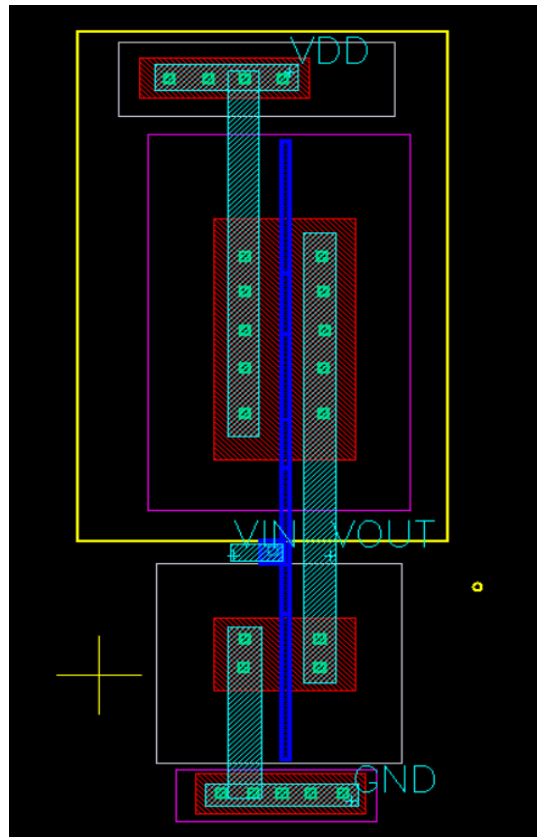
- e. What are the noise margins  $NM_L$  and  $NM_H$  of your design?

ANS:

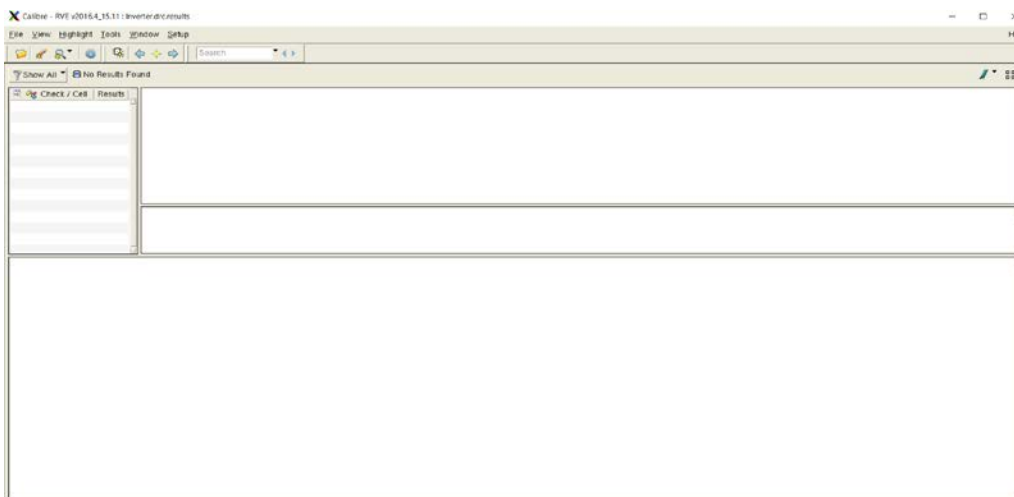
```
NML = 0.755-0.092 = 0.663
NMH = 1.675-1.034 = 0.641
```

- f. Complete the layout (including DRC and LVS). Show figures of your layout with DRC and LVS reports.

layout



DRC:



LVS



Problem 2

- a. Connect all three inputs together and design the PMOS sizes such that the transition point happens at  $V_{out} = 0.5 \cdot V_{DD}$  when  $V_{in}$  is  $0.5 \cdot V_{DD}$ , the same as the inverter in Q1. All three PMOS sizes should be the same.

ANS:

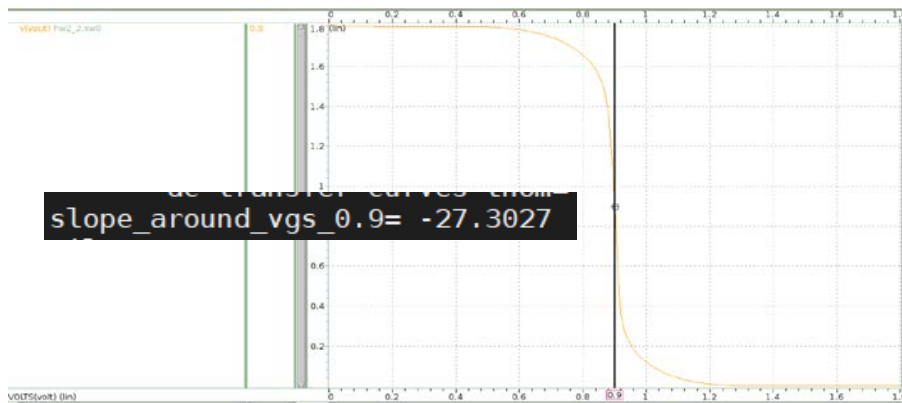
$$W/L = 2.217u/0.2u$$

- b. What is the ratio between PMOS and NMOS? How is it compared to the answer to Q1b and why?

ANS:  $\frac{(W/L)_p}{(W/L)_n} = 0.411$ , the ratio in Q1b is 3.37.  $0.411/3.37 = 0.122 \approx 1/9$ . 因為兩題的  $\beta$  ration 都假設為 1。且 NAND3 一個 NMOS width 變成原本的 3 倍(根據題目), 但因為串聯, 所以等效(指: 3 個 NMOS 一起看) length 也變 3 倍, 所以等效上 Q1b 的 NMOS 一樣。為了維持跟 Q1b 一樣的 beta ratio 且 NAND3 並聯 3 個 PMOS, 所以一個 PMOS width 會變成原本的 1/3 (length 固定的情況下), 且, 所以單獨看一個 NMOS 跟一個 PMOS 比例會變成原本的  $(1/3)/3 = 1/9$ 。但因為並聯 3 個 PMOS 跟 PMOS 直接 width\*3 有些微差距 (NMOS 串聯同理), 以及受到 CLM 的影響所以有誤差。

- c. Simulate and plot the DC voltage transfer curve of this inverter as  $V_{out}$  vs.  $V_{in}$  (with all three inputs tied together).

ANS:



- d. Find the values of  $V_{IL}$ ,  $V_{OH}$ ,  $V_{IH}$ , and  $V_{OL}$  at points with slope of  $-1$ .

ANS:

Use the same hspice code in Q1

```
vil= 772.3760m
voh=  1.6912
vih=  1.0235
vol=  93.9149m
```

- e. What are the noise margins  $NM_L$  and  $NM_H$  of this design? How are they compared to those of the inverter in Q1? Explain reasons for the difference.

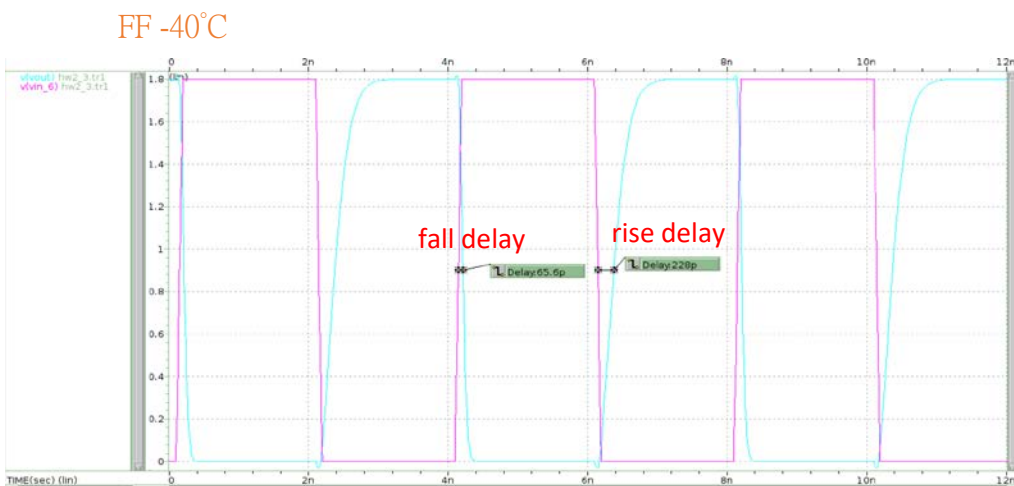
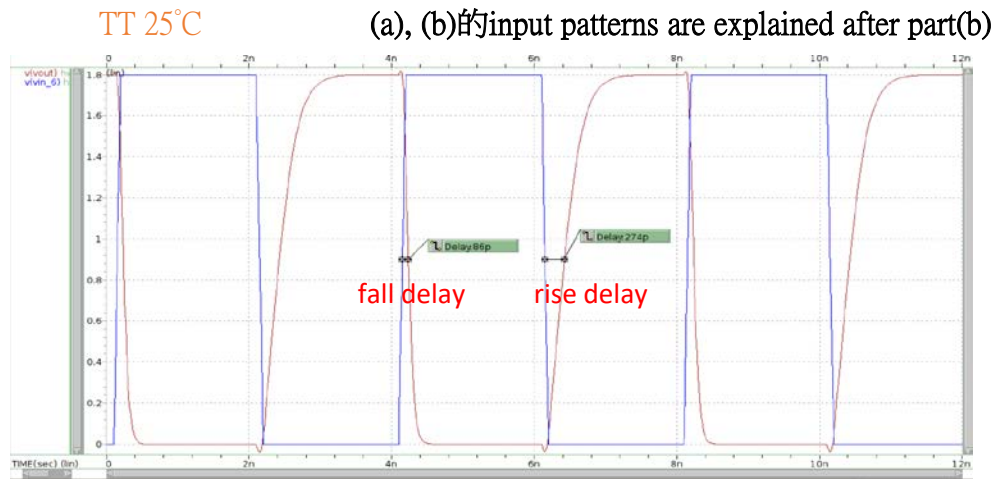
ANS:

$$NML=0.772-0.093=0.679 \quad NMH=1.6912-1.0235=0.667$$

Difference: According to \*.lis file in hspice, beta ratio gets closer to 1. And I noticed that the DC transfer curve's slope gets steeper(-20 in Q1b, -27 in Q2) around  $V_{gs} = 0.9$ , noise margin becomes larger.

### Problem 3

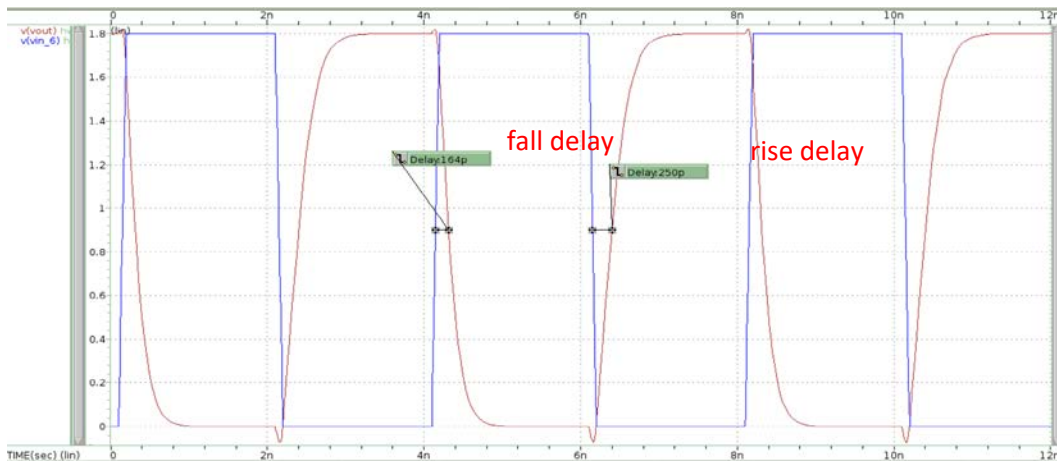
- a. Simulate the contamination delays for both rising and falling output. For both rising and falling cases, explain the input pattern that results in this shortest delay.



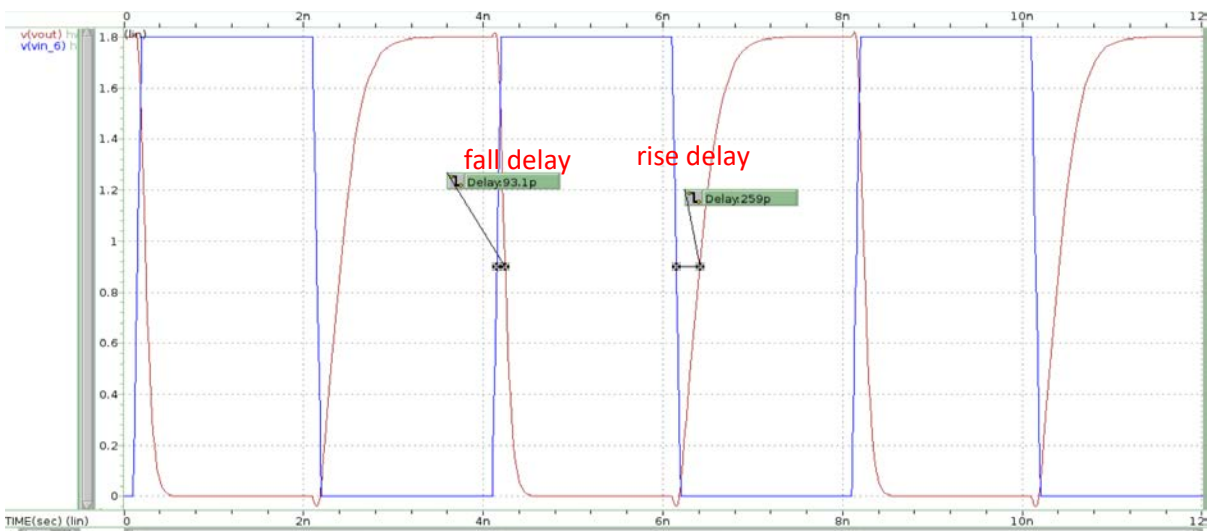
SS 125°C



SF 25°C



FS 25°C

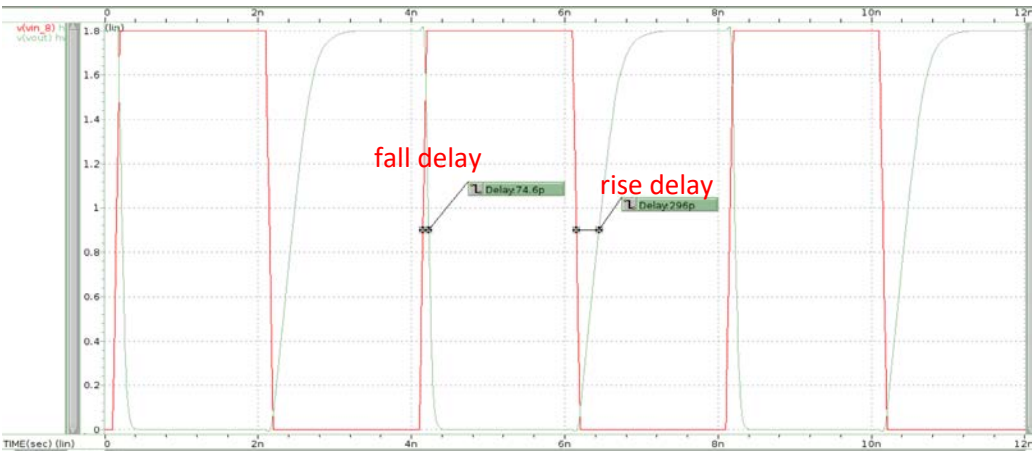


b. Simulate the worst-case propagation delays for both rising and falling output. For both rising and falling cases, explain the input patterns that result in this worst-case propagation delay.

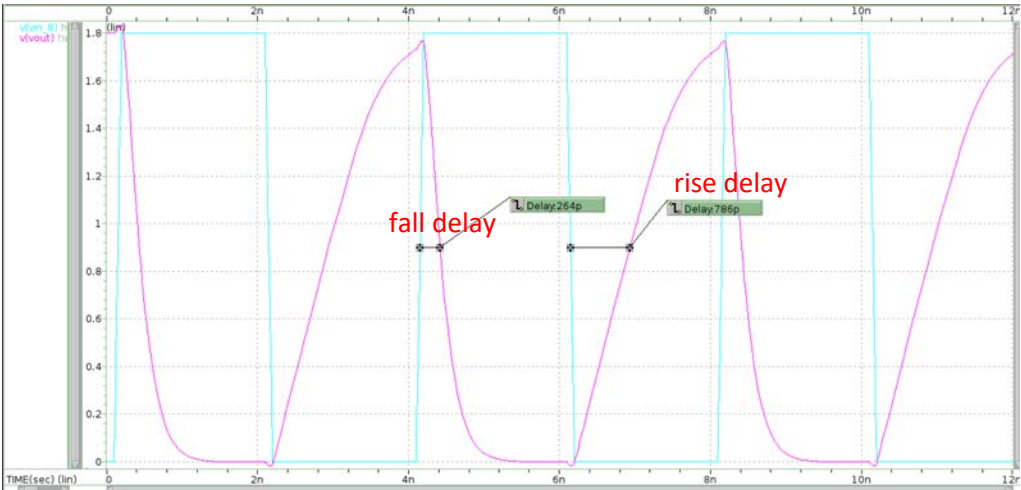
TT 25°C



FF -40°C

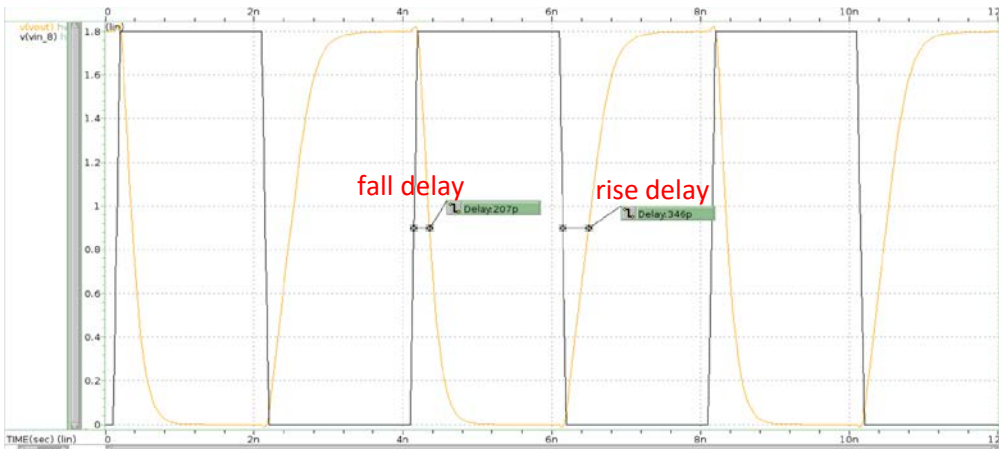


SS 125°C

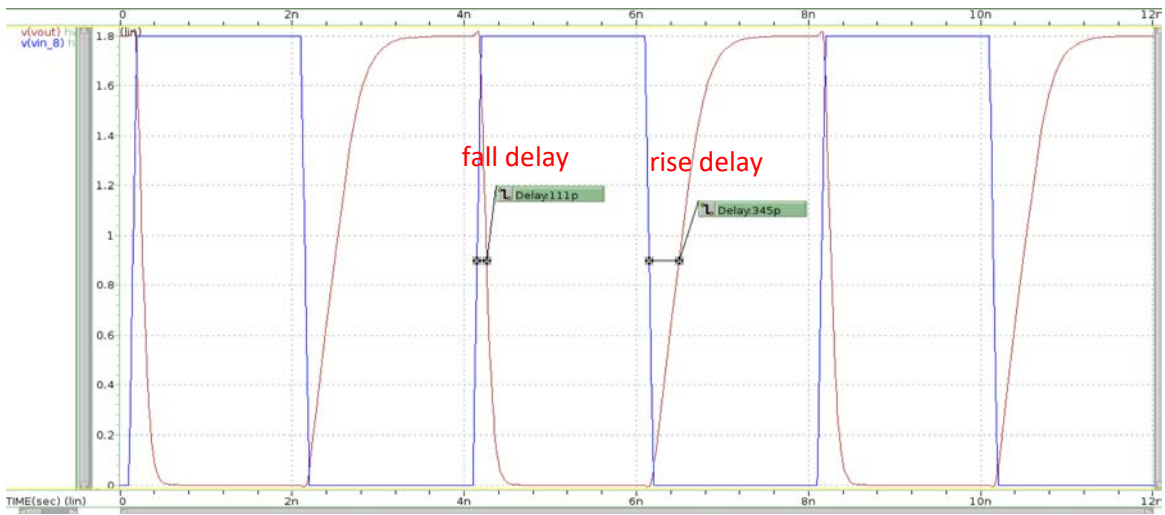




# SF 25°C

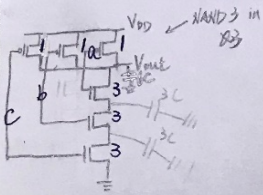
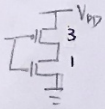


# FS 25°C



# Input pattern explained!!

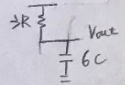
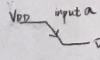
unit inverter in BI



$(\frac{R}{3})_p = (\frac{R}{3})_n$  in in  
 $Q_1 = 3:1$  del  
 $= 8:07:2:17$   
 $= 3:1$

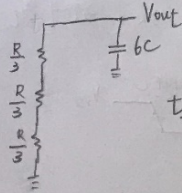
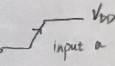
① Only a is switching

rise delay:  $V_{out}(0^-) = 0$



$$t_{rise\ delay} = 18RC$$

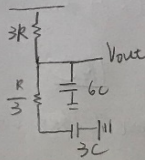
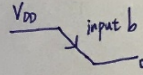
fall delay:  $V_{out}(0^-) = V_{DD}$



$$t_{fall\ delay} = 6C \cdot (R) = 6RC$$

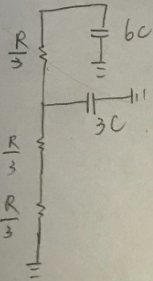
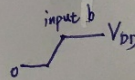
② Only b is switching

rise delay:  $V_{out}(0^-) = 0$



$$t_{rise\ delay} = 3R(6C + 3C) = 27RC$$

fall delay:  $V_{out}(0^-) = V_{DD}$

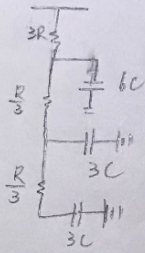
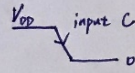


$$t_{fall\ delay} = 6C(R) + 3C(\frac{2}{3}R) = 8RC$$



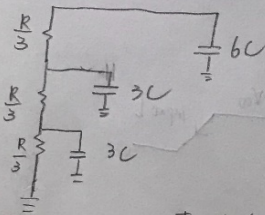
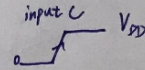
③ Only C is switching

rise delay:  $V_{out}(0^-) = 0$



$$t_{\text{rise\_delay}} = 3R(3C + 3C + 6C) = \underline{36RC}$$

fall delay:  $V_{out}(0^-) = V_{DD}$



$$t_{\text{fall\_delay}} = 6C(R) + 3C\left(\frac{2}{3}R\right) + 3C\left(\frac{R}{3}\right)$$

$$= \underline{9RC}$$

∴ When only a is switching, it's fastest (best case; contamination delay)

∴ C is slowest (worst case; propagation delay)

c. Repeat the above two questions across the following 5 corners. Show the waveforms with proper markers and complete the following table.

Process	Temperature	$t_{cdr}$	$t_{cdf}$	$t_{pdr}$	$t_{pdf}$
TT	25°C	275.324ps	86.017ps	362.504ps	100.7664ps
FF	-40°C	227.489ps	65.637ps	295.949ps	74.591ps
SS	125°C	553.499ps	213.721ps	786.171ps	263.788ps
SF	25°C	250.21ps	164.09ps	345.681ps	206.971ps
FS	25°C	259.679ps	93.065ps	344.883ps	110.713ps

d. Please also submit the sp netlist along with your report.

NAND3 sub-circuit for both contamination and propagation delays

```

*****
* auCdl Netlist:
*
* Library Name: VLSI
* Top Cell Name: NAND3
* View Name: schematic
* Netlisted on: Oct 18 00:00:07 2019
*****

*.BIPOLAR
*.RESI = 2000
*.RESVAL
*.CAPVAL
*.DIOPERI
*.DIOAREA
*.EQUATION
*.SCALE METER
*.MEGA
.PARAM width = 2.217u

*****
* Library Name: VLSI
* Cell Name: NAND3
* View Name: schematic
*****

.SUBCKT NAND3 VDD Vin_8 Vin_7 Vin_6 Vout gnd

```

```

*.PININFO VDD:I Vin:I Vout:O gnd:O
MM6 Vout Vin_6 VDD VDD p_18 L=200.0n w='width'
MM7 Vout Vin_7 VDD VDD p_18 L=200.0n w='width'
MM8 Vout Vin_8 VDD VDD p_18 L=200.0n w='width'
MM2 net24 Vin_8 gnd gnd n_18 W=5.4u L=200.0n
MM1 net28 Vin_7 net24 gnd n_18 W=5.4u L=200.0n
MM0 Vout Vin_6 net28 gnd n_18 W=5.4u L=200.0n
.ENDS

```

\*.sp file for Contamination delays

```

.prot
.lib 'cic018.l' TT
.unprot
.option post
.inc 'nand.spi'
X1 VDD Vin_8 Vin_7 Vin_6 Vout gnd NAND3
*voltage source
v1 VDD 0 1.8
v2 Vin_8 0 1.8
v3 Vin_7 0 1.8
VPULSE Vin_6 0 PULSE 0 1.8 100p 100p 100p 1900p 4n
*capacitor
C1 Vout gnd 100f
*analysis
.tran 0.01n 12n
.meas tran fall_delay Trig V(Vin_6)=0.9 rise=2 Targ V(Vout)=0.9 fall=2
.meas tran rise_delay Trig V(Vin_6)=0.9 fall=2 Targ V(Vout)=0.9 rise=2
.op
*different condition
.alter
.lib 'cic018.l'ff
.temp -40
.alter
.lib 'cic018.l'ss
.temp 125
.alter
.lib 'cic018.l'sf
.temp 25
.alter
.lib 'cic018.l'fs
.temp 25
.end

```

\*.sp file for propagation delays

```
.prot
.lib 'cic018.l' TT
.unprot
.option post
.inc 'nand.spi'
X1 VDD Vin_8 Vin_7 Vin_6 Vout gnd NAND3
*voltage source
v1 VDD 0 1.8
VPULSE Vin_8 0 PULSE 0 1.8 100p 100p 100p 1900p 4n
v3 Vin_7 0 1.8
V4 Vin_6 0 1.8
*capacitor
C1 Vout gnd 100f
*analysis
.tran 0.01n 12n
.meas tran fall_delay Trig V(Vin_8)=0.9 rise=2 Targ V(Vout)=0.9 fall=2
.meas tran rise_delay Trig V(Vin_8)=0.9 fall=2 Targ V(Vout)=0.9 rise=2
.op
*different condition
.alter
.lib 'cic018.l'ff
.temp -40
.alter
.lib 'cic018.l'ss
.temp 125
.alter
.lib 'cic018.l'sf
.temp 25
.alter
.lib 'cic018.l'fs
.temp 25
.end
```